

Notice of References Cited	Application/Control No. 10/637,171	Applicant(s)/Patent Under Reexamination AMARU ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,974	01-2005	Wachtel, David C.	707/101
	B	US-			
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	D	US-			
	E	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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